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BiNbO₄ Ceramics in Microwaves: Synthesis and Characterization

T. S. M. Fernandes^{(1)*}, A. J. M. Sales⁽¹⁾, J. S. Almeida^(1,2), M. A. S. Silva⁽¹⁾, A. C. F. Silva⁽²⁾ and

A. S. B. Sombra (1,2)

(1) Telecommunications and Materials Science and Engineering Laboratory (LOCEM)

<u>sombra@fisica.ufc.br</u>,

(2) Physics Department, Federal University of Ceará - UFC, 60455-760 Fortaleza – CE – Brazil www.fisica.ufc.br, * Corresponding author.

Abstract – The sintering behavior, microstructure and microwave dielectric properties of BiNbO4 ceramics have been investigated. The phase-forming temperature (from orthorhombic to triclinic phase) of BiNbO4 ceramics during sintering is lower than that $(1025 \circ C)$ of BiNbO4 ceramics. The variations of dielectric constant and Q value are also investigated. These compounds were prepared by the traditional solid state method. The phase purity and lattice parameters were studied by powder X-ray diffraction (XRD).

In this research, the properties dielectrics in microwaves of BiNbO₄ with phase transition was investigated as a function of sintering temperature. It is necessary to study the intrinsic properties of BiNbO₄ with phase transition to predict and control the dielectric properties at microwaves frequencies [1]. BiNbO₄ ceramics were prepared by the conventional mixed oxide method. The raw materials, Bi₂O₃ and Nb₂O₅, which had higher purity than 99,9%, were mixed for 2 hours in mill of high rotation with balls of ZrO₂, later roasted to several temperatures by 3h. Crystalline phases of the calcined powders and the sintered specimens were identified by XRD pattern analysis in the range 20 – 80° of using Cu Kα radiation. However, the phase BiNbO₄ roasted in the temperature of 850 °C, it presented a quite good result. The dielectric constant (*K*) and the unloaded $Q(1/\tan\delta)$ of the specimens at 4-6 GHz were measured by Hakki and Coleman's method. It can be studied for application in microwave divice materials and in ceramic capacitors of multilayers [1,2].



Figure 1: Dielectric permittivity (ϵ_i) as afunction concentration a) Doping PVA and b) Doping TEOS.

Figure 2: a) Tan loss as a function temperature. b) Dielectric permittivity (ϵ_r) as a function temperature.

[1] D. Liu, Y. Liu, S.Q. Huang, X. Yao, J. Am. Ceram. Soc. 76 (1993) 2129–2132.

[2] Eung Soo Kim, Woong Choi, Effect of phase transition on the microwave dielectric properties of BiNbO₄ – Journal of the European Ceramic Society 26 (2006) 1761-1776